Ignition IGBT 18 Amps, 400 Volts

N-Channel D2PAK

This Logic Level Insulated Gate Bipolar Transistor (IGBT) features monolithic circuitry integrating ESD and Overvoltage clamped protection for use in inductive coil drivers applications. Primary uses include Ignition, Direct Fuel Injection, or wherever high voltage and high current switching is required.

Features

- Ideal for Coil-on-Plug Applications
- Gate-Emitter ESD Protection
- Temperature Compensated Gate-Collector Voltage Clamp Limits Stress Applied to Load
- Integrated ESD Diode Protection
- New Design Increases Unclamped Inductive Switching (UIS) Energy Per Area
- Low Threshold Voltage to Interface Power Loads to Logic or Microprocessor Devices
- Low Saturation Voltage
- High Pulsed Current Capability
- Integrated Gate-Emitter Resistor (R_{GE})
- Emitter Ballasting for Short-Circuit Capability
- Pb-Free Package is Available

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V _{CES}	430	V_{DC}
Collector-Gate Voltage	V _{CER}	430	V_{DC}
Gate-Emitter Voltage	V _{GE}	18	V_{DC}
Collector Current-Continuous @ T _C = 25°C - Pulsed	I _C	18 50	A _{DC} A _{AC}
ESD (Human Body Model) R = 1500 Ω , C = 100 pF	ESD	8.0	kV
ESD (Machine Model) R = 0 Ω , C = 200 pF	ESD	800	V
Total Power Dissipation @ T _C = 25°C Derate above 25°C	P _D	115 0.77	W W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	−55 to +175	°C

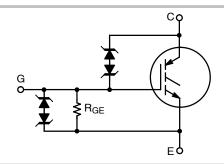
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



ON Semiconductor®

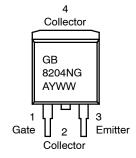
http://onsemi.com

18 AMPS, 400 VOLTS $V_{CE(on)} \le 2.0 \text{ V } @$ $I_C = 10 \text{ A}, V_{GE} \ge 4.5 \text{ V}$





MARKING DIAGRAM



GB8204N = Device Code A = Assembly Location

Y = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NGB8204NT4	D ² PAK	800 / Tape & Reel
NGB8204NT4G	D ² PAK (Pb-Free)	800 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

UNCLAMPED COLLECTOR-TO-EMITTER AVALANCHE CHARACTERISTICS (-55° \leq T $_{J}$ \leq 175°C)

Characteristic	Symbol	Value	Unit
Single Pulse Collector–to–Emitter Avalanche Energy V_{CC} = 50 V, V_{GE} = 5.0 V, Pk I_L = 21.1 A, L = 1.8 mH, Starting T_J = 25°C V_{CC} = 50 V, V_{GE} = 5.0 V, Pk I_L = 18.3 A, L = 1.8 mH, Starting T_J = 125°C	E _{AS}	400 300	mJ
Reverse Avalanche Energy V_{CC} = 100 V, V_{GE} = 20 V, Pk I _L = 25.8 A, L = 6.0 mH, Starting T _J = 25°C	E _{AS(R)}	2000	mJ

MAXIMUM SHORT-CIRCUIT TIMES $(-55^{\circ}C \le T_{J} \le 150^{\circ}C)$

Short Circuit Withstand Time 1 (See Figure 17, 3 Pulses with 10 ms Period)	t _{sc1}	750	μs
Short Circuit Withstand Time 2 (See Figure 18, 3 Pulses with 10 ms Period)	t _{sc2}	5.0	ms

THERMAL CHARACTERISTICS

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{ heta JC}$	1.3	°C/W
Thermal Resistance, Junction-to-Ambient D ² PAK (Note 1)	$R_{ heta JA}$	50	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds (Note 2)	TL	275	°C

^{1.} When surface mounted to an FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Temperature	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Collector-Emitter Clamp Voltage	BV _{CES}	I _C = 2.0 mA	$T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	380	395	420	V_{DC}
		I _C = 10 mA	$T_J = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	390	405	430	
Zero Gate Voltage Collector Current	I _{CES}		T _J = 25°C	-	2.0	10	μA _{DC}
		$V_{CE} = 350 \text{ V}, V_{GF} = 0 \text{ V}$	T _J = 150°C	-	10	40*	
		•GE = 0 •	T _J = -40°C	-	1.0	10	
Reverse Collector-Emitter Leakage	I _{ECS}		T _J = 25°C	-	0.7	1.0	mA
Current		V _{CE} = -24 V	T _J = 150°C	-	12	25*	
			T _J = -40°C	-	0.1	1.0	
Reverse Collector-Emitter Clamp	B _{VCES(R)}		T _J = 25°C	27	33	37	V_{DC}
Voltage		$I_C = -75 \text{ mA}$	T _J = 150°C	30	36	40	
			T _J = -40°C	25	32	35	
Gate-Emitter Clamp Voltage	BV _{GES}	I _G = 5.0 mA	$T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	11	13	15	V_{DC}
Gate-Emitter Leakage Current	I _{GES}	V _{GE} = 10 V	$T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	384	640	700	μA _{DC}
Gate Emitter Resistor	R _{GE}	_	$T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	10	16	26	$_{k}\Omega$
ON CHARACTERISTICS (Note 3)			•				
Gate Threshold Voltage	V _{GE(th)}	I _C = 1.0 mA, V _{GE} = V _{CE}	T _J = 25°C	1.1	1.4	1.9	V_{DC}
			T _J = 150°C	0.75	1.0	1.4	
			$T_J = -40^{\circ}C$	1.2	1.6	2.1*	
Threshold Temperature Coefficient (Negative)	-	_	-	-	3.4	_	mV/°C

^{*}Maximum Value of Characteristic across Temperature Range.

^{2.} For further details, see Soldering and Mounting Techniques Reference Manua, SOLDERRM/D.

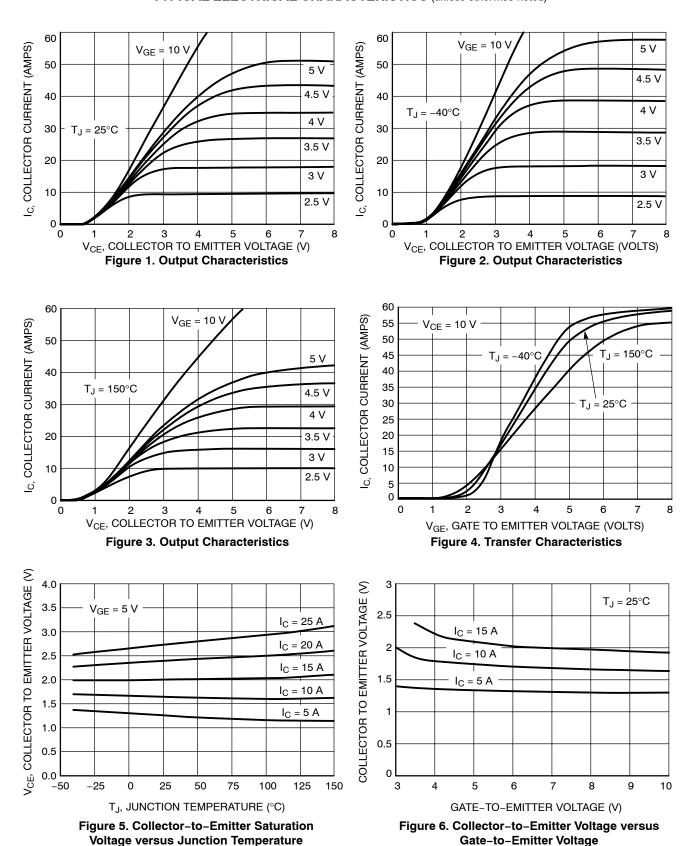
^{3.} Pulse Test: Pulse Width \leq 300 $\mu\text{S},$ Duty Cycle \leq 2%.

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Temperature	Min	Тур	Max	Unit
ON CHARACTERISTICS (Note 3)				•			
Collector-to-Emitter On-Voltage	V _{CE(on)}		T _J = 25°C	1.0	1.4	1.6	V_{DC}
		I _C = 6.0 A, V _{GE} = 4.0 V	T _J = 150°C	0.9	1.3	1.6	
		VGE - 4.0 V	T _J = -40°C	1.1	1.45	1.7*	-
			T _J = 25°C	1.3	1.6	1.9*	
		I _C = 8.0 A, V _{GE} = 4.0 V	T _J = 150°C	1.2	1.55	1.8	
		VGE = 4.5 V	T _J = −40°C	1.4	1.6	1.9*	
			T _J = 25°C	1.4	1.8	2.0	
		I _C = 10 A, V _{GE} = 4.0 V	T _J = 150°C	1.5	1.8	2.0	
		VGE = 1.5 V	T _J = -40°C	1.4	1.8	2.1*	
			T _J = 25°C	1.8	2.2	2.5	
		I _C = 15 A, V _{GE} = 4.0 V	T _J = 150°C	2.0	2.4	2.6*	
		$T_{J} = -40^{\circ}C$ $T_{J} = 25^{\circ}C$	1.7	2.1	2.5	1	
			T _J = 25°C	1.3	1.8	2.0*	
		I _C = 10 A, V _{GE} = 4.5 V	T _J = 150°C	1.3	1.75	2.0*	
		I GE	T _J = -40°C	1.4	1.8	2.0*	
Forward Transconductance	gfs	$V_{CE} = 5.0 \text{ V},$ $I_{C} = 6.0 \text{ A}$	$T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	8.0	14	25	Mhos
DYNAMIC CHARACTERISTICS							
Input Capacitance	C _{ISS}			400	800	1000	pF
Output Capacitance	C _{OSS}	V _{CC} = 25 V, V _{GE} = 0 V f = 1.0 MHz	$T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	50	75	100	
Transfer Capacitance	C _{RSS}			4.0	7.0	10	
SWITCHING CHARACTERISTICS							
Turn-Off Delay Time (Resistive)	t _{d(off)}	V_{CC} = 300 V, I_{C} = 6.5 A R_{G} = 1.0 k Ω , R_{L} = 46 Ω ,	T _J = 25°C	-	4.0	10	μSec
Fall Time (Resistive)	t _f	V_{CC} = 300 V, I_{C} = 6.5 A R_{G} = 1.0 k Ω , R_{L} = 46 Ω ,	T _J = 25°C	_	9.0	15	
Turn-On Delay Time	t _{d(on)}	$\begin{aligned} V_{CC} &= 10 \text{ V, I}_{C} = 6.5 \text{ A} \\ R_{G} &= 1.0 \text{ k}\Omega, \\ R_{L} &= 1.5 \Omega \end{aligned}$	T _J = 25°C	-	0.7	4.0	μSec
Rise Time	t _r	V_{CC} = 10 V, I_{C} = 6.5 A R_{G} = 1.0 k Ω , R_{I} = 1.5 Ω	T _J = 25°C	-	4.5	7.0	

^{*}Maximum Value of Characteristic across Temperature Range. 3. Pulse Test: Pulse Width \leq 300 μ S, Duty Cycle \leq 2%.

TYPICAL ELECTRICAL CHARACTERISTICS (unless otherwise noted)



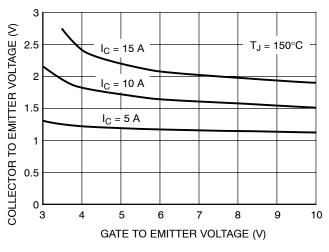


Figure 7. Collector-to-Emitter Voltage versus Gate-to-Emitter Voltage

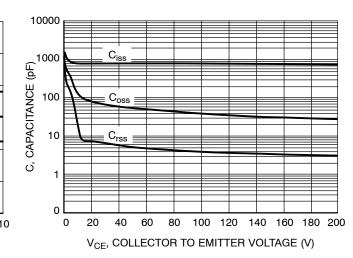


Figure 8. Capacitance Variation

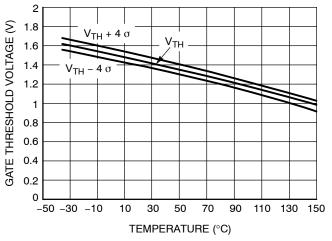


Figure 9. Gate Threshold Voltage versus Temperature

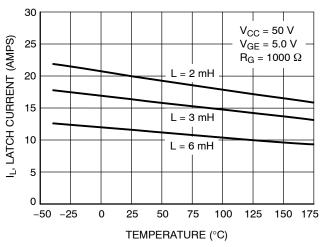


Figure 10. Minimum Open Secondary Latch Current versus Temperature

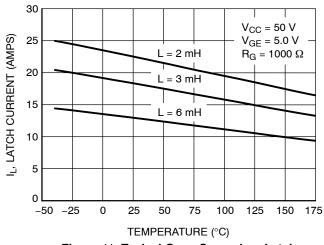


Figure 11. Typical Open Secondary Latch
Current versus Temperature

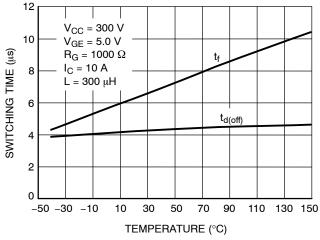


Figure 12. Inductive Switching Fall Time versus Temperature

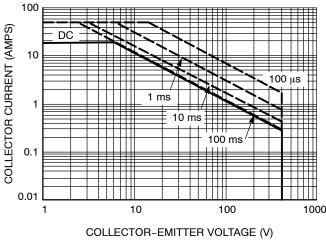


Figure 13. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at $T_A = 25$ °C)

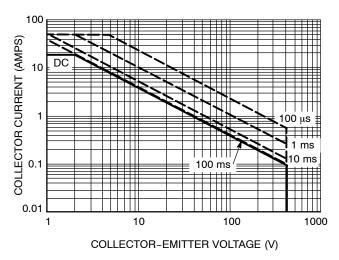


Figure 14. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at $T_A = 125$ °C)

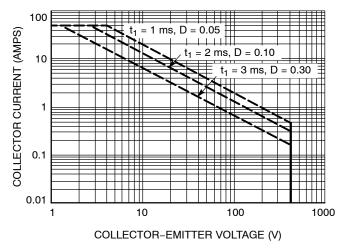


Figure 15. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at $T_C = 25^{\circ}C$)

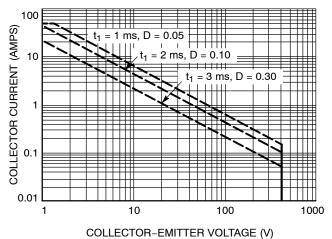
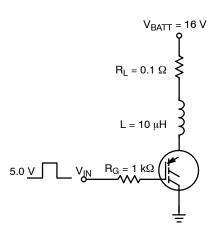


Figure 16. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at $T_C = 125$ °C)





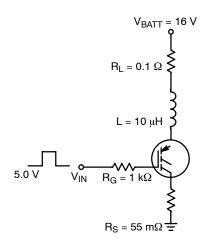


Figure 18. Circuit Configuration for Short Circuit Test #2

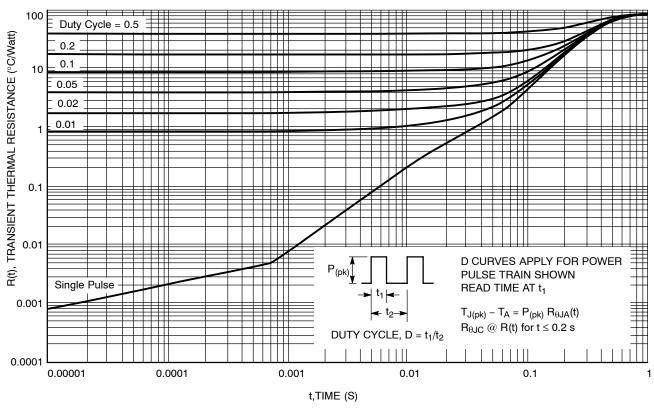
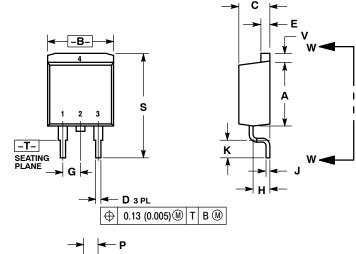


Figure 19. Transient Thermal Resistance (Non-normalized Junction-to-Ambient mounted on minimum pad area)

PACKAGE DIMENSIONS

D²PAK 3 CASE 418B-04 **ISSUE J**



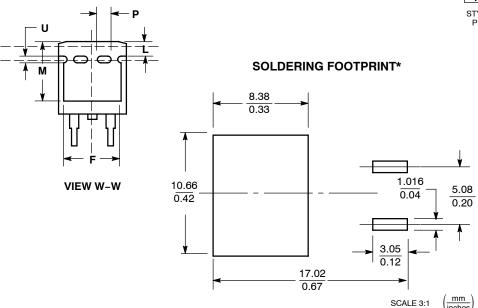
NOTES:

- DIMENSIONING AND TOLERANCING
 PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: INCH.
- 418B-01 THRU 418B-03 OBSOLETE, NEW STANDARD 418B-04.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.340	0.380	8.64	9.65	
В	0.380	0.405	9.65	10.29	
С	0.160	0.190	4.06	4.83	
D	0.020	0.035	0.51	0.89	
E	0.045	0.055	1.14	1.40	
F	0.310	0.350	7.87	8.89	
G	0.100	BSC	2.54 BSC		
Н	0.080	0.110	2.03	2.79	
J	0.018	0.025	0.46	0.64	
K	0.090	0.110	2.29	2.79	
L	0.052	0.072	1.32	1.83	
M	0.280	0.320	7.11	8.13	
N	0.197	REF	5.00 REF		
Р	0.079	REF	2.00 REF		
R	0.039	REF	0.99	REF	
S	0.575	0.625	14.60	15.88	
٧	0.045	0.055	1.14	1.40	

- STYLE 4: PIN 1. GATE 2. COLLECTOR 3. EMITTER

 - 4. COLLECTOR



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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